

Search Notes**Application/Control No.**

10/660,957

Examiner

Ellen C. Tran

Applicant(s)/Patent under Reexamination

HAYES ET AL.

Art Unit

2134

SEARCHED

Class	Subclass	Date	Examiner
380	247	7/26/2007	ET
380	249	7/26/2007	ET
380	250	7/26/2007	ET

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES,	7/26/2007	ET
NPL - IEEE XPLOR	7/26/2007	ET
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTIONS	7/26/2007	ET
INTERFERENCE SEARCH - USPG PUB AND CLASS COMBINED WITH TEXT SEARCH	7/26/2007	ET

INTERFERENCE SEARCHED

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INTERFERENCE SEARCH - USPG PUB AND CLASS COMBINED WITH TEXT	7/26/2007	ET	